

ITW

Docket No.: P2001,0356

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By: 

Date: September 17, 2007

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/715,073 Confirmation No.: 3310
Applicant : Torsten Seidel et al.
Filed : November 17, 2003
Title : CONFIGURATION AND METHOD FOR DETECTING DEFECTS ON
A SUBSTRATE IN A PROCESSING TOOL
Art Unit : 2624
Examiner : Samir A. Ahmed
Docket No. : P2001,0356
Customer No. : 24131

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR § 1.97

Hon. Commissioner for Patents
Alexandria, VA 22313-1450

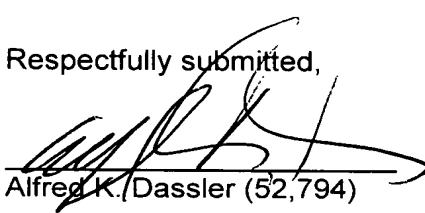
Sir:

In accordance with 37 CFR § 1.98 copies of the following patents and/or publications are cited herewith:

English Translation of Korea patent office Unexamined Patent Publication KR 2001-0035816 (Lee et al.), dated May 07, 2001.

In accordance with 37 CFR § 1.97(e) the undersigned herewith states that each item of information contained in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Respectfully submitted,


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